# Tucana 94GHz MMIC

#### TU-W1330303

**GaAs PHEMT MEDIUM POWER AMPLIFIER 95 – 105GHz** 

#### Overview

TU-W1330303 is a 4-stage MMIC medium power amplifier that covers from 95GHz to 105GHz. The TU-W1330303 provides over 20dB of stable gain, and a P3 power output of 16dBm from a +4V supply voltage.

All bond pads and the die backside are gold plated. The TU-W1330303 MMIC is compatible with conventional die attach methods, as well as thermo-compression and thermosonic wire bonding, making it ideal for MCM and hybrid microcircuit applications. All data shown herein is provisional and is measured with the chip in a 50 Ohm environment and contacted with RF probes.

A single or cascaded packaged version of the device is also available with WR10 waveguide input and output.

#### **Features**

- 95 105GHz
- >20dB Gain
- >16dBm P3 Output
- Unconditionally Stable

## **Applications**

- Narrow Bandwidth Millimetrewave Imaging
- High Resolution Radar
- Sensing
- P2P Communications; short haul/high capacity/low interference links















# **Specification Overview**

Parameter	Min.	Тур.	Max.	Units
Frequency	95		105	GHz
Gain		15		dB
Input Return Loss	6	8		dB
Output Return Loss	4	10		dB
Maximum OP Power		10	16	dBm
Drain Voltage		4		V
Nominal Gate Voltage*		0		V
Current		225		mA

#### Notes

The tests indicated have all been performed with 100pF de-coupling capacitors on all bias pads.
All tests are carried out at 25°C.

\*Should be adjusted to ensure the correct current is drawn

# **Absolute Maximum Ratings**

Parameter	Rating	
Gate Voltage	-5V to 0.2V dc	
Drain Voltage	6V	
Drain Current	400mA	
RF Input Power	5dBm	
Storage Temperature	−65°C to +150°C	
Channel Temperature	+150°C	
Operating Temperature	-40°C to +85°C	



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features proprietary protection circuitry, damage may occur on devices subjected to ESD. Proper ESD precautions should be taken to avoid performance degradation or loss of functionality.



## **Measured Performance Data**

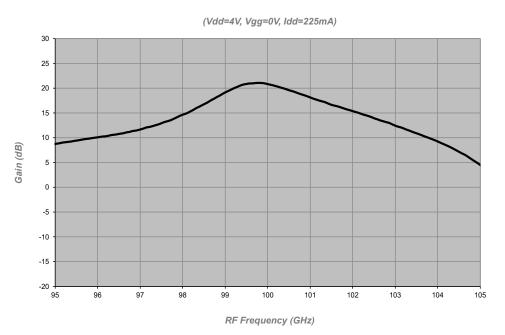
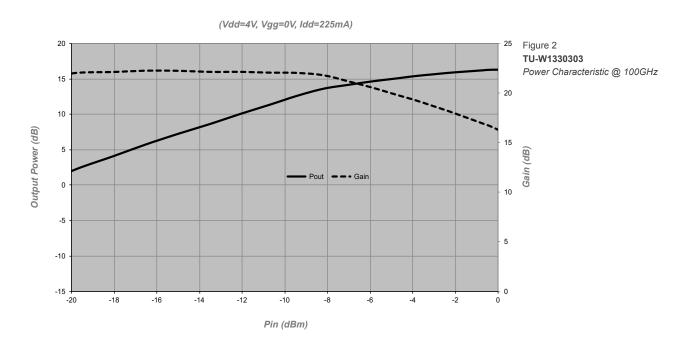


Figure 1 TU-W1330303 Gain



## **Measured Performance Data**

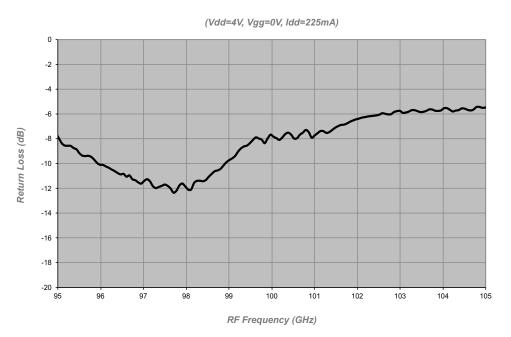


Figure 3 **TU-W1330303** *Input Return Loss* 

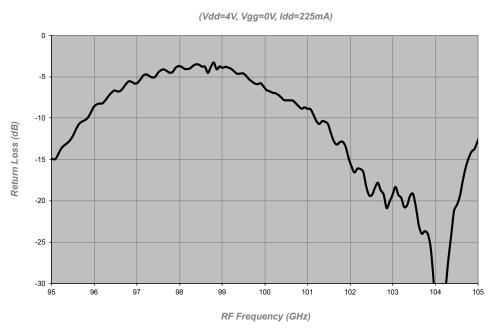
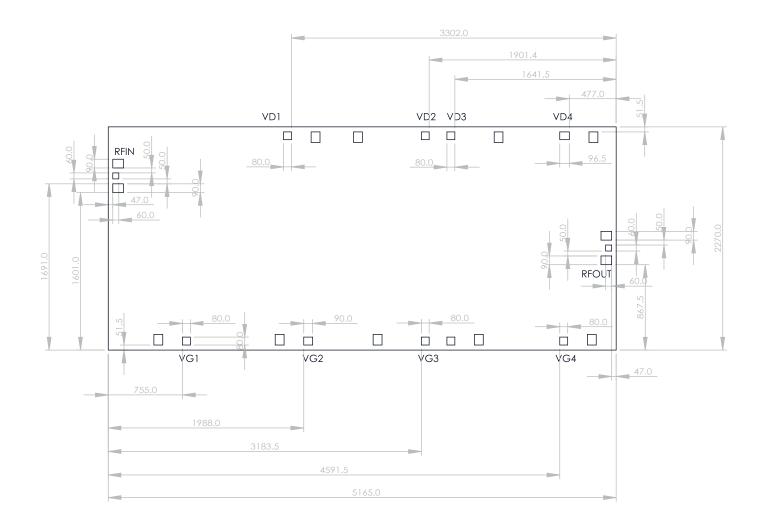


Figure 4 **TU-W1330303**Output Return Loss



# **Outline Drawing**





# **Pad Descriptions**

Name	Description
RFIN	Input RF pad. This pad is ac coupled.
RFOUT	Output RF pad. This pad is ac coupled.
VDx	Drain bias pad for stage x
VGx	Gate bias pad for stage x.
воттом	The die backside must be connected to RF/dc ground.

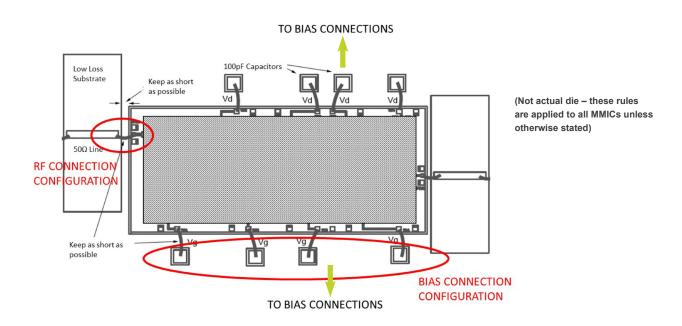
#### Notes

- 1. All dimensions are in um.
- 2. Typical dc bond pads are 80um square.
- 3. RF bond pads are 60um square.
- 4. All pads have gold metalisation.
- 5. Gold backside metalisation.
- 6. Backside metal is ground.
- 7. Connections are not required for unlabelled bond pads.
- 8. Die thickness is 50um

#### **Die Packing Information**

All die are delivered using gel-paks unless otherwise requested.

## **General Notes on Assembly**



Die should be mounted on conductive material such as gold-plated metal to provide a good ground and suitable heat sink, if necessary.

- 1. Attaching the die using Au/Sn preforms is preferable. The Eutectic melt for Au/Sn occurs at approximately 280°C so the die (plus mount and preform) is initially heated up to 180°C and then it is heated for approximately 10 seconds to 280°C using a nitrogen heat gun. The device will survive 10 seconds at this temperature. The static breakdown for GaAs devices is approximately 330°C.
- 2. Pure, dry Nitrogen should be used as the heat source
- If the devices cannot be lifted/ placed by a vacuum device, then ESD die-lifting tweezers are preferable.
- 4. Supply lines should be decoupled with 100pF capacitors. Larger planar capacitors could be used if available.
- 5. Aluminium wire must not be used.

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